Masatoshi Jo

List of Publications by Year
in descending order

16	301	933447 10	996975 15
papers	citations	h-index	g-index

16	16	16	126
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Interactions of H2 with the Ni(110) surface: EELS and LEED studies. Surface Science, 1985, 154, 417-434.	1.9	48
2	Oxygen adsorption on Pd(110) at 300 K-low-energy electron diffraction and electron energy loss spectroscopy studies. Chemical Physics Letters, 1986, 131, 106-111.	2.6	46
3	Adsorbed states of oxygen on Pd(1 1 0) â€" Vibrational electron energy loss spectroscopy and low-energy electron diffraction studies. Solid State Communications, 1986, 60, 257-260.	1.9	43
4	Adsorbed states of hydrogen on Pd(1 1 0): Vibrational electron energy loss spectroscopy and low-energy electron diffraction studies. Solid State Communications, 1985, 55, 639-642.	1.9	37
5	Adsorbed state and vibrational excitation of N2 on Pd(110). Surface Science, 1987, 180, 421-432.	1.9	32
6	Direct, simultaneous determination of XPS background and inelastic differential cross section using Tougaard's algorithm. Surface Science, 1994, 320, 191-200.	1.9	21
7	Hydrogen chemisorption on Ni(110) by high-resolution electron energy loss spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 1983, 29, 273-278.	1.7	20
8	Electron energy loss spectra of a Pd(110) clean surface. Solid State Communications, 1986, 58, 75-77.	1.9	18
9	Adsorbed states of hydrogen on the Ni(110) surface. Surface Science, 1985, 151, L179-L184.	1.9	16
10	Auger electron peaks of Cu in XPS. Applied Surface Science, 1996, 100-101, 11-14.	6.1	12
11	Relation between the shape of measured loss function and the resolution of the XPS spectrum. Applied Surface Science, 1999, 144-145, 49-53.	6.1	3
12	XPS inelastic background optimization: algorithm and results. Surface and Interface Analysis, 2003, 35, 729-737.	1.8	2
13	Optimization of XPS Inelastic Background using Tougaardâ€™s Formula. Journal of Surface Analysis (Online), 2002, 9, 295-301.	0.1	1
14	Estimation of IMFP except for a constant factor using only XPS background-optimized peak intensities and cross sections. Journal of Surface Analysis (Online), 2014, 20, 166-170.	0.1	1
15	Restoration of Loss Function in Very Difficult Case. Journal of Surface Analysis (Online), 2002, 9, 302-305.	0.1	1
16	An almost knowledge-free approach to XPS intensity evaluation where use of atomic photoemission cross sections suffices for yielding material-specific inelastic background. Journal of Electron Spectroscopy and Related Phenomena, 2017, 215, 36-56.	1.7	0